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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Keisuke MURAYA, et al.

Serial No: 10/780,610

Group Art Unit: 2829

Confirmation No. 3175

Filed: February 19, 2004

Examiner: Jimmy Nguyen

For: APPARATUS FOR MEASURING VOLTAGE FLUCTUATION WAVEFORM IN SEMICONDUCTOR INTEGRATED CIRCUIT, AND SEMICONDUCTOR INTEGRATED CIRCUIT HAVING FUNCTION FOR MEASURING VOLTAGE FLUCTUATION WAVEFORM

**LETTER TO THE EXAMINER SUBMITTING
CORRECTED AND/OR FORMAL DRAWINGS**

Box ISSUE FEE

Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

ATTENTION: OFFICIAL DRAFTSPERSON

Sir:

Enclosed is a Replacement Sheet for Figs. 15-16 to comply with the drawing requirements on the Notice of Allowability.

It is respectfully requested that the Replacement Sheet be entered in the above-referenced application.

Respectfully submitted,

STAAS & HALSEY LLP

Date: December 16, 2004

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